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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 22.0003-01
CB Certificate No.: 50600440 ITL

Schedule Number: IECQ-L ULTW 22.0003-01-S Rev No.: 4 Revision Date: 2025/01/07 Page 1 of 4

Appendix-1 (50600440 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
ESD Human Body Model (HBM)	ANSI/ESDA/JEDEC JS-001 AEC-Q100-002 AEC-Q101-001 MIL-STD-883
ESD Machine Model (MM)	JESD22-A115
ESD Charged Device Model (CDM)	ANSI/ESDA/JEDEC JS-002 AEC-Q100-011 AEC-Q101-005
IC Latch-Up Test (LU)	JESD78 AEC-Q100-004 MIL-STD-883
Preconditioning Test	JESD22-A113 IPC/JEDEC J-STD-020 IPC/JEDEC J-STD-033
Acoustic Microscopy for Nonhermetic Encapsulated Electronic Components	IPC/JEDEC J-STD-035
High / Low Temperature Operating Teat (HTOL / LTOL)	JESD22-A108 MIL-STD-883 MIL-STD-750
Temperature and Bias Life Test	AEC-Q101 AEC-Q102 JESD22-A108 MIL-STD-750 MIL-STD-883

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan



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High Temperature Gate Bias (HTGB)	AEC-Q101 JESD22-A108
High Temperature Reverse Bias (HTRB)	AEC-Q101 JESD22-A108
High Humidity High Temperature Reverse Bias (H3TRB)	AEC-Q101 JESD22-A101
High Temperature Storage Life Test	JESD22-A103
Low Temperature Storage Life Test	JESD22-A119
Early Life Failure Rate (ELFR)	JESD74 AEC-Q100-008 JESD85
Highly Accelerated Temperature and Humidity Stress Test (HAST)	JESD22-A110
Accelerated Moisture Resistance - Unbiased HAST (UHAST) & Unbiased Autoclave (AC)	JESD22-A118 JESD22-A102
Temperature-Humidity Biased Life Test	JESD22-A101
Cycled Temperature and Humidity Biased Life Test (Moisture Resistance)	JESD22-A100 MIL-STD-883
Temperature Cycling Test	JESD22-A104 MIL-STD-883
Power and Temperature Cycling Test	JESD22-A105
Intermittent Operational Life	MIL-STD-750
Temperature Shock Test	MIL-STD-810

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Moisture Sensitivity Level (MSL)	JESD22-A113
, , ,	IPC/JEDEC J-STD-020
	IPC/JEDEC J-STD-033
Thermal Stress Test	IPC/JEDEC J-STD-020
	IPC-TM-650 Method 2.6.27
Moisture and Insulation Resistance Test	IPC-TM-650 Method 2.6.3
and	IPC-TM-650 Method 2.6.25
Conductive Anodic Filament (CAF)	
Resistance	
Program / Erase Endurance and Data	JESD22-A117
Retention Stress Test (EDR)	AEC-Q100-005
Dye and Pull Test (Dye and Pry Test)	IPC-TM-650 Method 2.4.53
Solderability Test	IPC J-STD-002
	IPC J-STD-003
Conductive Resistance Test	IPC-TM-650 Method 2.5.32
	IPC-9701
PCB Hot Oil Test	IPC-TM-650 Method 2.4.6
PCB Solder Float Resistance Test	IPC-TM-650 Method 2.4.13
	JESD22-B117
	JESD22-B116
	AEC-Q100-001
	AEC-Q100-010
Solder Ball Shear Test	AEC-Q101
Solder Ball Shear Test	AEC-Q102
	AEC-Q104
	IPC-TM-650 Method 2.4.42.3
	MIL-STD-883
	MIL-STD-750
Wire Bond Pull Test	JESD22-B120
	AEC-Q101
	AEC-Q102
	AEC-Q104
	IPC-TM-650 Method 2.4.42.3
	MIL-STD-883

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	MIL-STD-750
Board Flex Test	JESD22-B113
	AEC-Q101-002
	AEC-Q200-005
	EIAJ ED-4702A
	MIL-STD-883
	IPC-9702
	JESD22-B105
Lead Fatigue Test	AEC-Q100
(Lead Integrity Test)	AEC-Q104
	MIL-STD-883
	JESD22-A107
Salt Spray Test	MIL-STD-883
(Salt Atmosphere Test)	MIL-STD-750
	ISO 10289

Technical Reviewer of DQS: Date: 01/07/2025

